Search Notes			

Application/Control No.	

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Applicant(s)/Patent under

10/774,535

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Art Unit

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SEARCHED				
Class	Subclass	Date	Examiner	
315	169.1- 169.4	4/13/2006	LA	
313	498-505	4/13/2006	LA	
345	77, 80	4/13/2006	LA	
345	83, 204	4/13/2006	LA	
345	690	4/13/2006	LA	

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Subclass	Date	Examiner		
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	DATE	EXMR
Updated EAST prior art text search (see "Examiner Search Notes")	4/13/2006	LA
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